

Power MOSFET

PRODUCT SUMMA	RY	
V _{DS} (V)	-25	50
R _{DS(on)} (Ω)	$V_{GS} = -10 \text{ V}$	1.2
Q _g (Max.) (nC)	8.7	
Q _{gs} (nC)	2.2	!
Q _{gd} (nC)	4.1	
Configuration	Sing	le

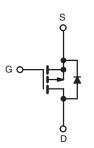
FEATURES

- Surface mount
- Available in tape and reel
- Dynamic dV/dt rating
- Repetitive avalanche rated
- P-channel
- · Fast switching
- Ease of paralleling









P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T	_C = 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	-250	V	
Gate-Source Voltage			V_{GS}	± 20	7 v	
Continuous Drain Current	V -+ 10.V	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$		-2.1		
	V _{GS} at - 10 V	T _C = 100 °C	ID	-1.69	А	
Pulsed Drain Current ^a			I _{DM}	-8.8		
Linear Derating Factor				0.025	W/°C	
Linear Derating Factor (PCB Mount) e				0.017		
Single Pulse Avalanche Energy b			E _{AS}	100	mJ	
Avalanche Current ^a			I _{AR}	-1.1	Α	
Repetitive Avalanche Energy ^a			E _{AR}	0.31	mJ	
Maximum Power Dissipation	T _C =	T _C = 25 °C		3.1	w	
Maximum Power Dissipation (PCB Mount) e	T _A =	T _A = 25 °C		2.0		
Peak Diode Recovery dV/dt ^c			dV/dt	-5.5	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C	
Soldering Recommendations (Peak Temperature)	d for	10 s		300	1	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = -25 V, starting T_J = 25 °C, L = 7.7 mH, R_g = 25 Ω , I_{AS} = -4.4 A (see fig. 12).
- c. $I_{SD} \le -4.4$ A, $dI/dt \le -75$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.
- e. When mounted on 1" square PCB (FR-4 or G-10 material).



THERMAL RESISTANCE RATINGS							
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient (PCB Mount) ^a	R _{thJA}	-	-	60	°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	-	40			

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static					L	L	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$		-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I _D = -1 mA	1	-0.091	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	V _{GS} , I _D = -250 μA	-2.0	-	-4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		-100 V, V _{GS} = 0 V	-	-	-100	μA
			', V _{GS} = 0 V, T _J = 125 °C	-	-	- 500	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = -10 V	$I_D = -0.66 \text{ A}^b$	-	1.2	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	-50 V, I _D = -0.66 A	0.82	-	-	S
Dynamic					ı	ı	
Input Capacitance	C _{iss}		$V_{GS} = 0 V$,		200	-	pF
Output Capacitance	C_{oss}	$V_{DS} = -25 \text{ V},$ f = 1.0 MHz, see fig. 5		-	94	-	
Reverse Transfer Capacitance	C_{rss}			-	18	-	
Total Gate Charge	Q_g		I _D = -4.0 A, V _{DS} = -80 V, see fig. 6 and 13 ^b	ı	-	8.7	nC
Gate-Source Charge	Q_gs	$V_{GS} = -10 \text{ V}$		1	-	2.2	
Gate-Drain Charge	Q_{gd}	See lig. 0 and 10	-	-	4.1	1	
Turn-On Delay Time	t _{d(on)}	V_{DD} = -50 V, I_{D} = -4.0 A, R_{G} = 24 Ω , R_{D} = 11 Ω , see fig. 10 ^b		-	10	-	ns
Rise Time	t _r			-	27	-	
Turn-Off Delay Time	t _{d(off)}			-	15	-	
Fall Time	t _f			-	17	-	
Internal Drain Inductance	L _D		Between lead, 6 mm (0.25") from		4.0	-	nЦ
Internal Source Inductance	L _S	package and center of die contact		-	6.0	-	- nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	-1.1	Α
Pulsed Diode Forward Current ^a	I _{SM}			-	-	-8.8	
Body Diode Voltage	V_{SD}	T _J = 25 °C,	T _J = 25 °C, I _S = -1.1 A, V _{GS} = 0 V b		-	-5.5	V
Body Diode Reverse Recovery Time	t _{rr}	T 05.00 :			80	160	ns
Body Diode Reverse Recovery Charge	Q_{rr}	$T_J = 25 ^{\circ}\text{C}, I_F = -4.0 \text{A}, \text{dI/dt} = 100 \text{A/\mus}^{\text{b}}$		-	0.15	0.30	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	ırn-on time is negligible (turn	on is dor	ninated b	v L _s and	LD)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width $\leq 300~\mu s$; duty cycle $\leq 2~\%$.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

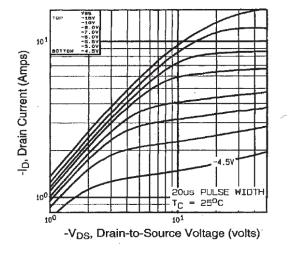


Fig. 1 - Typical Output Characteristics

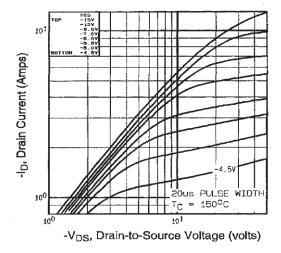


Fig. 2 - Typical Output Characteristics

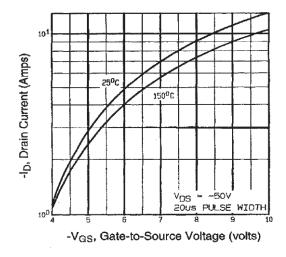


Fig. 3 - Typical Transfer Characteristics

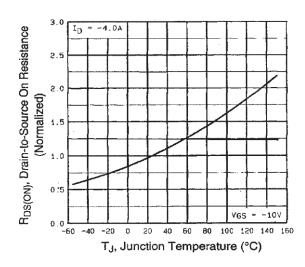


Fig. 4 - Normalized On-Resistance vs. Temperature



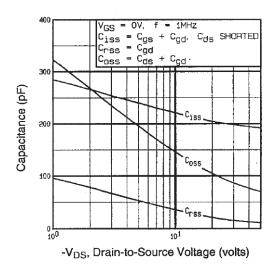


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

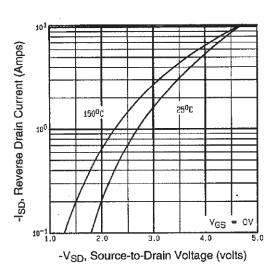


Fig. 7 - Typical Source-Drain Diode Forward Voltage

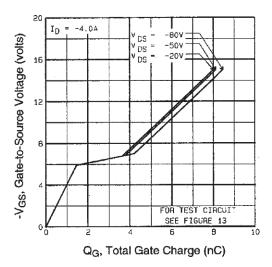


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

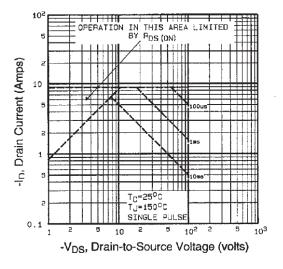


Fig. 8 - Maximum Safe Operating Area



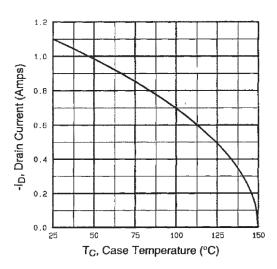


Fig. 9 - Maximum Drain Current vs. Case Temperature

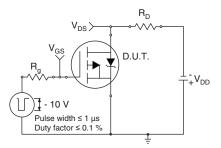


Fig. 10a - Switching Time Test Circuit

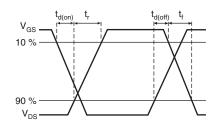


Fig. 10b - Switching Time Waveforms

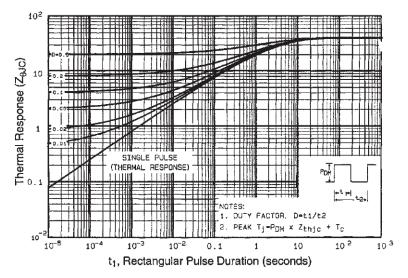


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



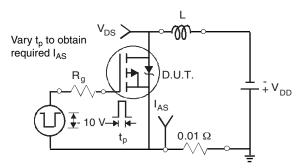


Fig. 12a - Unclamped Inductive Test Circuit

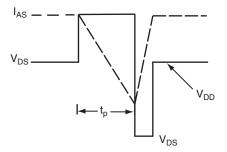


Fig. 12b - Unclamped Inductive Waveforms

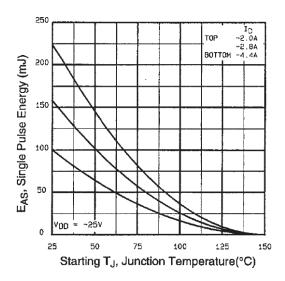


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

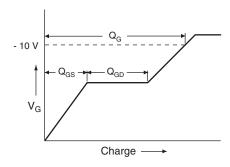


Fig. 13a - Basic Gate Charge Waveform

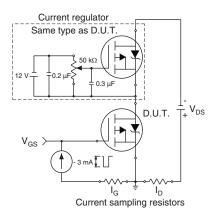
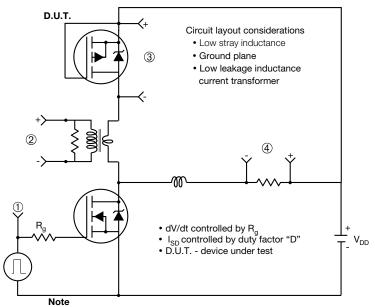


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



• Compliment N-Channel of D.U.T. for driver

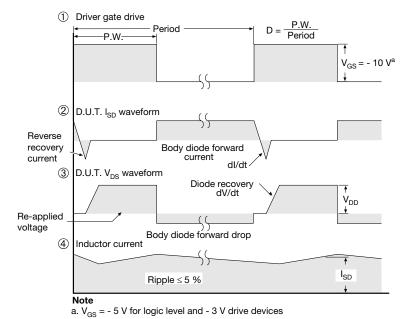
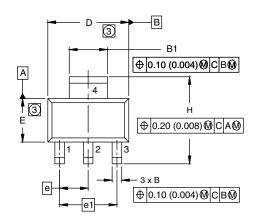
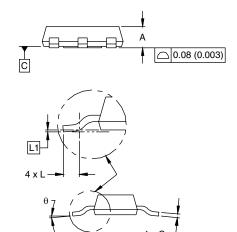


Fig. 14 - For P-Channel



SOT-223 (HIGH VOLTAGE)





DIM.	MILLI	METERS	INCHES		
	MIN.	MAX.	MIN.	MAX.	
Α	1.55	1.80	0.061	0.071	
В	0.65	0.85	0.026	0.033	
B1	2.95	3.15	0.116	0.124	
С	0.25	0.35	0.010	0.014	
D	6.30	6.70	0.248	0.264	
Е	3.30	3.70	0.130	0.146	
е	2.30 BSC		0.0905 BSC		
e1	4.60 BSC		0.181	BSC	
Н	6.71	7.29	0.264	0.287	
L	0.91	-	0.036	-	
L1	0.061 BSC		0.0024	BSC	
θ	-	10'	-	10'	

ECN: S-82109-Rev. A, 15-Sep-08

DWG: 5969

Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimensions are shown in millimeters (inches).
- 3. Dimension do not include mold flash.
- 4. Outline conforms to JEDEC outline TO-261AA.

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